

Notice of References Cited		Application/Control No. 09/652,962	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
		Examiner Mark L. Shibuya	Art Unit 1639	Page 1 of 1

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	C	US-5,512,131	04-1996	Kumar et al.	438/738
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NON-PATENT DOCUMENTS

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	U	Mrksich et al., TIBTECH June 1995, Vol. 13, pp. 228-235.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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